



# 15N40K-MT

*Power MOSFET*

## 15A, 400V N-CHANNEL POWER MOSFET

### DESCRIPTION

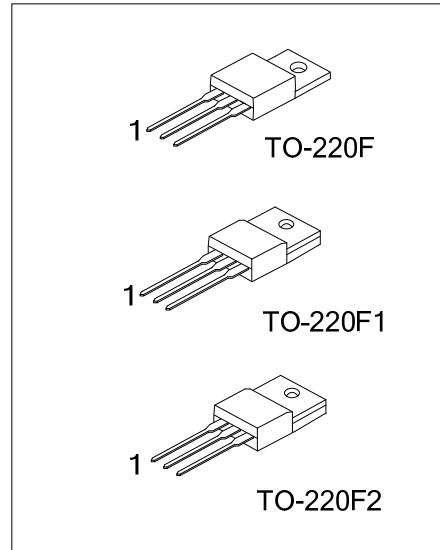
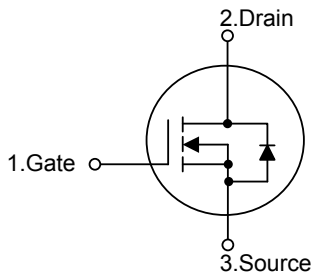
The UTC **15N40K-MT** is an N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology allows a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

The UTC **15N40K-MT** is generally applied in high efficiency switch mode power supplies.

### FEATURES

- \*  $R_{DS(ON)} \leq 0.30 \Omega @ V_{GS} = 10 V, I_D = 7.5 A$
- \* High Switching Speed

### SYMBOL



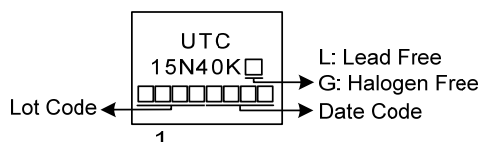
### ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
15N40KL-TF1-T	15N40KG-TF1-T	TO-220F1	G	D	S	Tube
15N40KL-TF2-T	15N40KG-TF2-T	TO-220F2	G	D	S	Tube
15N40KL-TF3-T	15N40KG-TF3-T	TO-220F	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>15N40KG-TF2-T</p> <p>(1) Packing Type</p> <p>(2) Package Type</p> <p>(3) Green Package</p>	<p>(1) T: Tube</p> <p>(2) TF1: TO-220F1, TF2: TO-220F2, TF3: TO-220F</p> <p>(3) G: Halogen Free and Lead Free, L: Lead Free</p>
---	---

### MARKING



■ ABSOLUTE MAXIMUM RATINGS ( $T_C=25^\circ\text{C}$ , unless otherwise specified.) (Note 5)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain to Source Voltage		$V_{DSS}$	400	V
Gate-Source Voltage		$V_{GSS}$	$\pm 30$	V
Drain Current	Continuous $T_C=25^\circ\text{C}$	$I_D$	15	A
	Pulsed (Note 2)	$I_{DM}$	30	A
Avalanche Energy		$E_{AS}$	756	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	2.01	V/ns
Power Dissipation ( $T_C=25^\circ\text{C}$ )		$P_D$	38	W
Junction Temperature		$T_J$	+150	$^\circ\text{C}$
Storage Temperature		$T_{STG}$	-55 ~ +150	$^\circ\text{C}$

- Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.  
 2. Repetitive Rating; Pulse width limited by maximum junction temperature.  
 3.  $L=30\text{mH}$ ,  $I_{AS}=7.1\text{A}$ ,  $V_{DD}=50\text{V}$ ,  $R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$   
 4.  $I_{SD}\leq 15\text{A}$ ,  $di/dt\leq 200\text{A}/\mu\text{s}$ ,  $V_{DD}\leq BV_{DSS}$ , Starting  $T_J=25^\circ\text{C}$   
 5. Drain current limited by maximum junction temperature.

■ THERMAL DATA

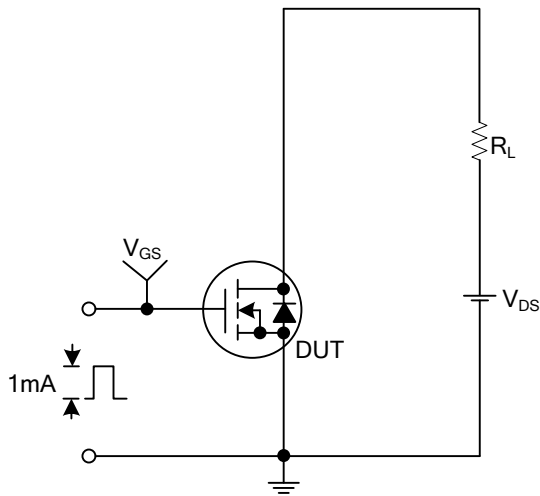
PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	$\theta_{JA}$	62.5	$^\circ\text{C}/\text{W}$
Junction to Case	$\theta_{JC}$	3.28	$^\circ\text{C}/\text{W}$

■ ELECTRICAL CHARACTERISTICS

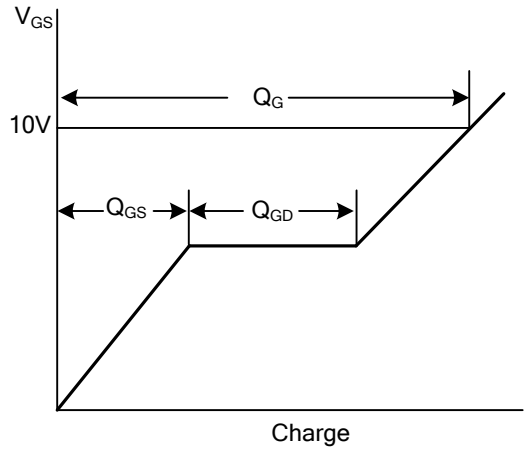
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$I_D=250\mu\text{A}$ , $V_{GS}=0\text{V}$ , $T_J=25^\circ\text{C}$	400			V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS}=400\text{V}$ , $V_{GS}=0\text{V}$			10	$\mu\text{A}$
		$V_{DS}=320\text{V}$ , $T_C=125^\circ\text{C}$			10	$\mu\text{A}$
Gate- Source Leakage Current	Forward	$I_{GSS}$			+100	nA
	Reverse					
<b>ON CHARACTERISTICS</b>						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS}=V_{DS}$ , $I_D=250\mu\text{A}$	2.0		4.0	V
Static Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10\text{V}$ , $I_D=7.5\text{A}$		0.23	0.30	$\Omega$
<b>DYNAMIC PARAMETERS</b>						
Input Capacitance	$C_{ISS}$	$V_{DS}=25\text{V}$ , $V_{GS}=0\text{V}$ , $f=1.0\text{MHz}$		1720		pF
Output Capacitance	$C_{OSS}$			220		pF
Reverse Transfer Capacitance	$C_{RSS}$			13		pF
<b>SWITCHING PARAMETERS</b>						
Total Gate Charge	$Q_G$	$V_{DS}=320\text{V}$ , $V_{GS}=10\text{V}$ , $I_D=15\text{A}$ (Note 1, 2)		45		nC
Gate to Source Charge	$Q_{GS}$			14		nC
Gate to Drain ("Miller") Charge	$Q_{GD}$			12		nC
Turn-ON Delay Time	$t_{D(ON)}$	$V_{DS}=100\text{V}$ , $I_D=15\text{A}$ , $R_G=25\Omega$ (Note 1, 2)		22		ns
Rise Time	$t_R$			25		ns
Turn-OFF Delay Time	$t_{D(OFF)}$			130		ns
Fall-Time	$t_F$			33		ns
<b>SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS</b>						
Maximum Body-Diode Continuous Current	$I_S$				15	A
Maximum Body-Diode Pulsed Current	$I_{SM}$				30	A
Drain-Source Diode Forward Voltage	$V_{SD}$	$I_{SD}=15\text{A}$ , $V_{GS}=0\text{V}$			1.4	V
Reverse Recovery Time (Note 1)	$t_{rr}$	$I_S=15\text{A}$ , $V_{GS}=0\text{V}$ ,		250		nS
Reverse Recovery Charge	$Q_{rr}$	$di/dt = 100\text{A}/\mu\text{s}$		7.8		$\mu\text{C}$

- Notes: 1. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ ; Duty Cycle  $\leq 2\%$ .  
 2. Essentially Independent of Operating Temperature Typical Characteristics.

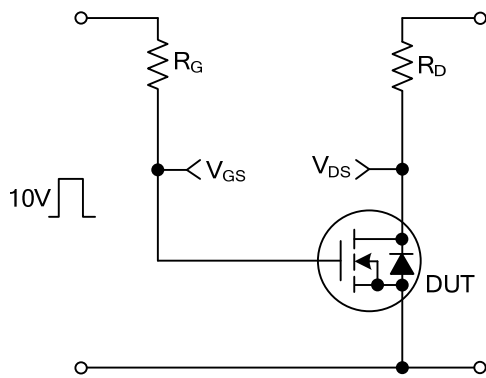
### ■ TEST CIRCUITS AND WAVEFORMS



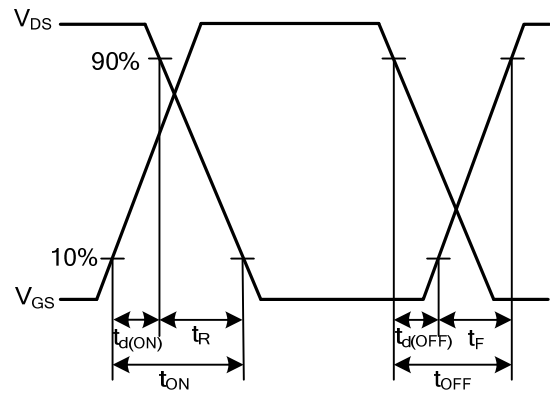
Gate Charge Test Circuit



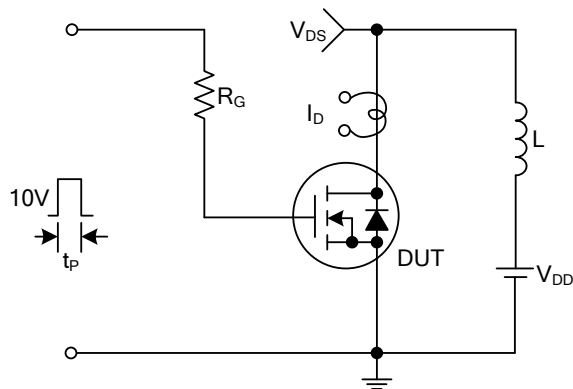
Gate Charge Waveforms



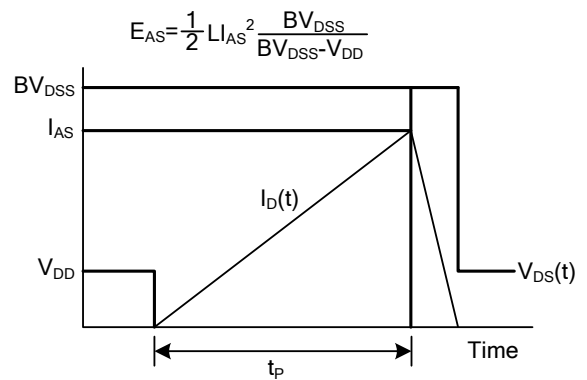
Resistive Switching Test Circuit



Resistive Switching Waveforms



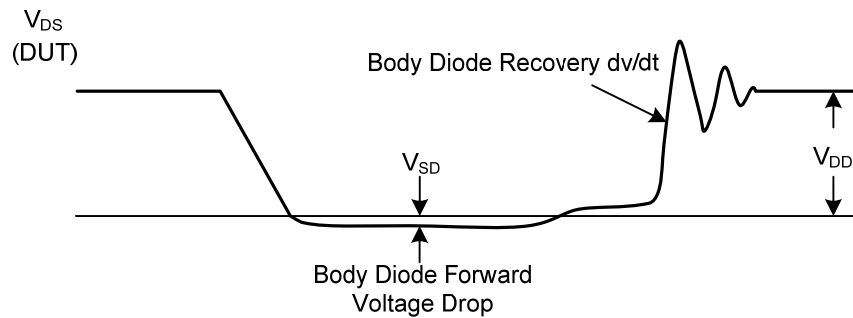
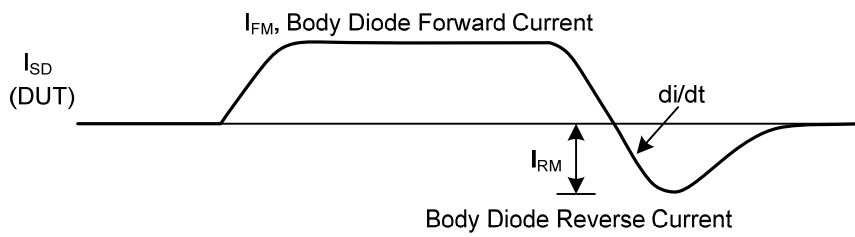
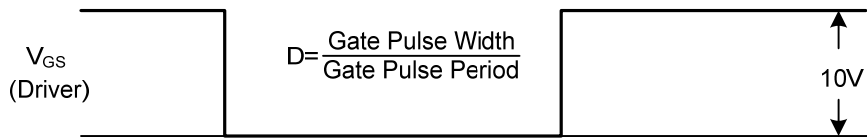
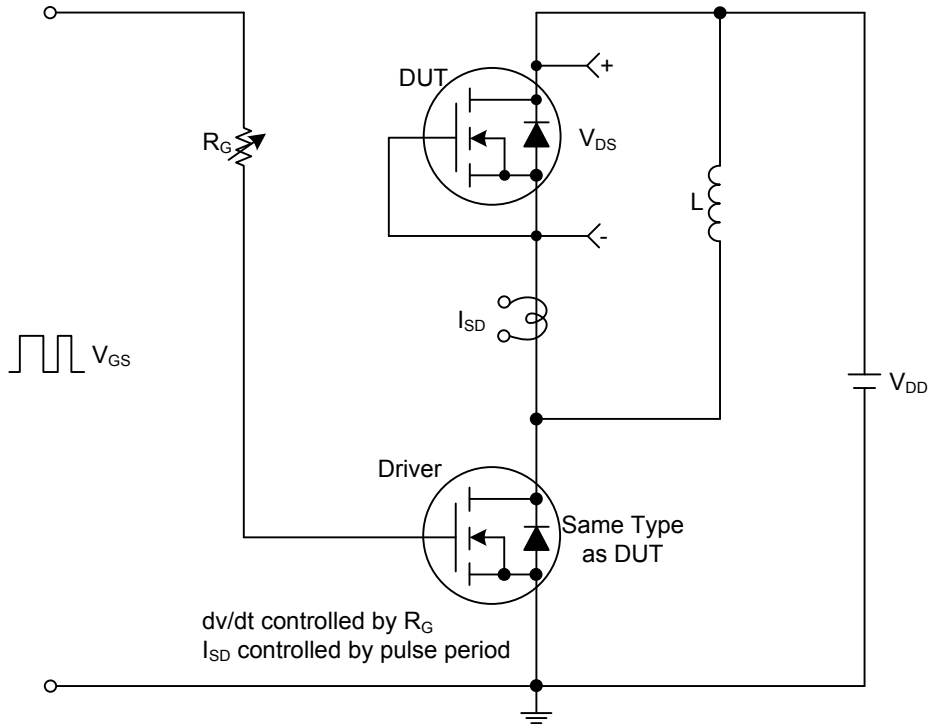
Unclamped Inductive Switching Test Circuit



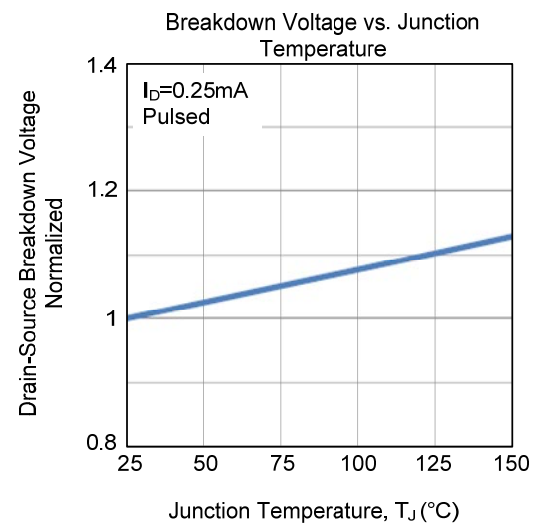
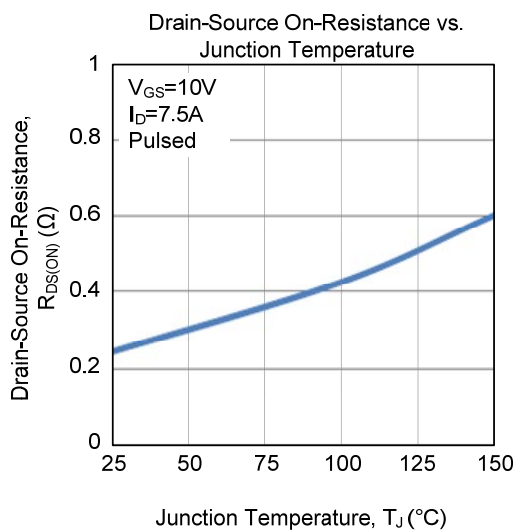
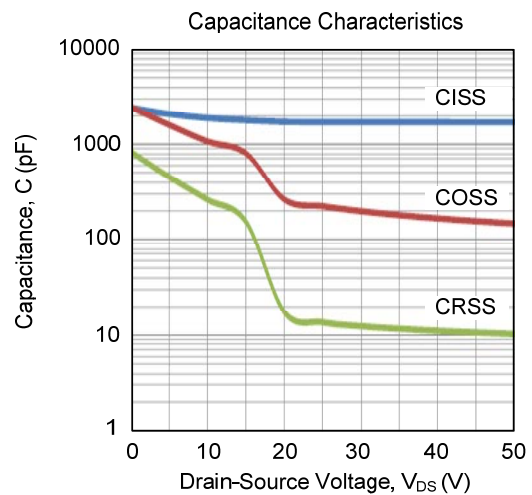
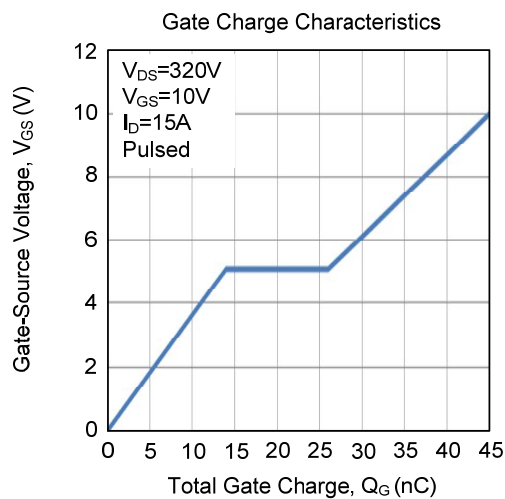
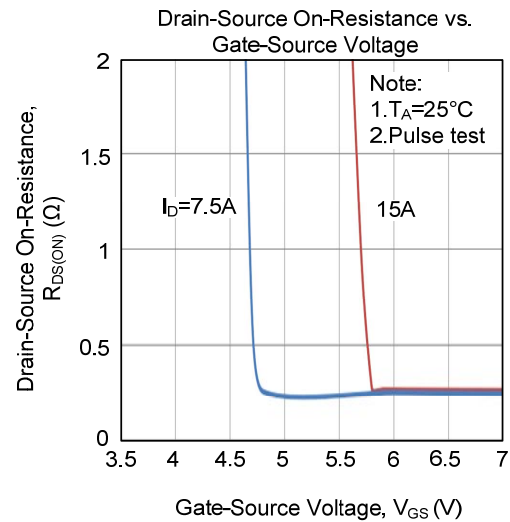
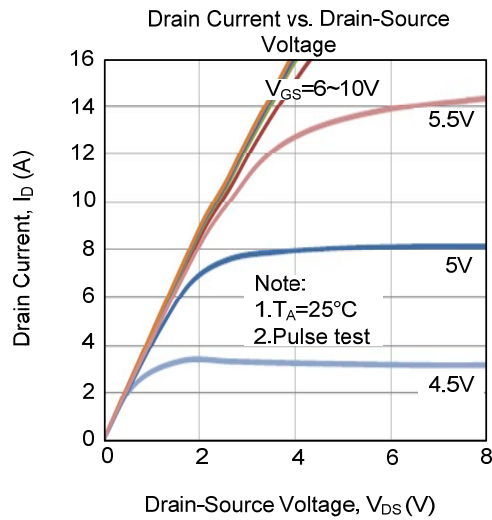
Unclamped Inductive Switching Waveforms

■ TEST CIRCUITS AND WAVEFORMS

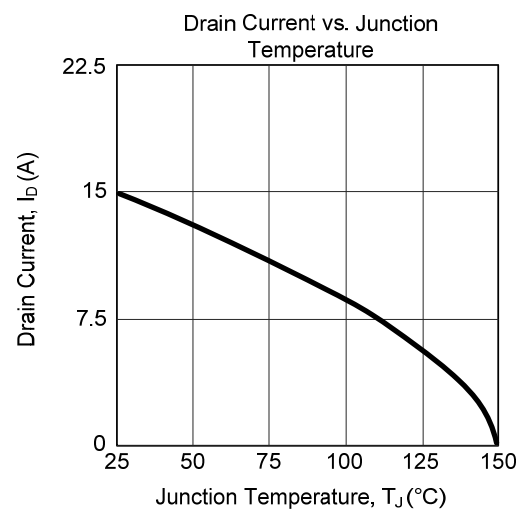
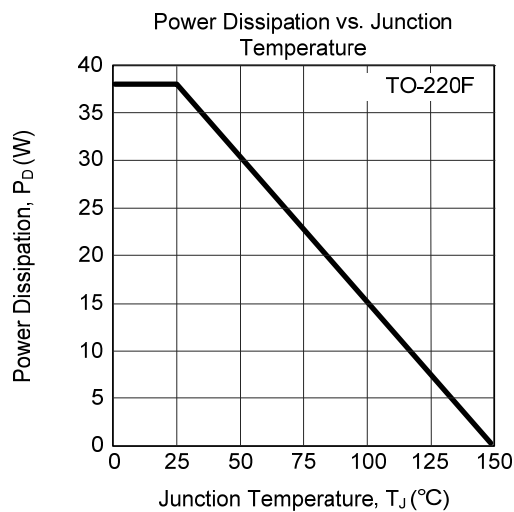
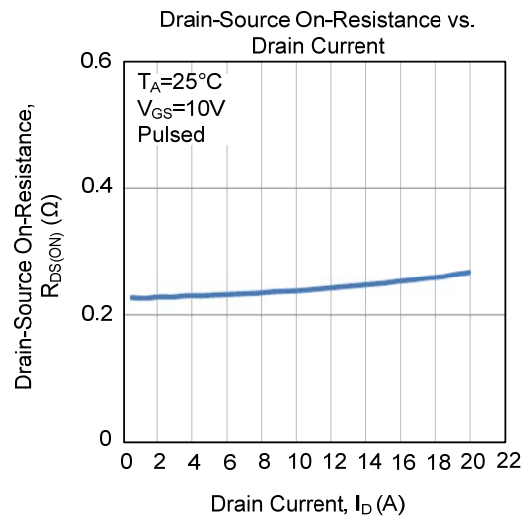
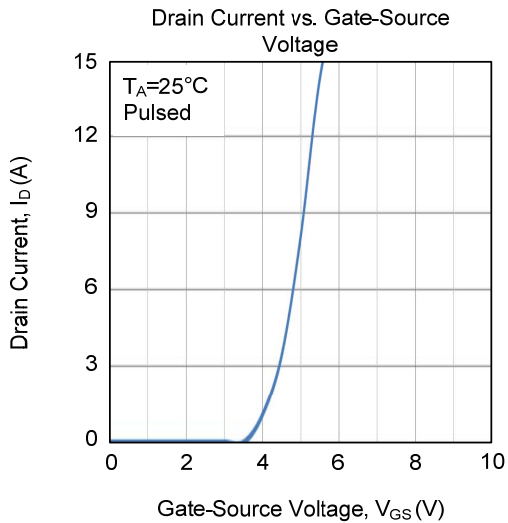
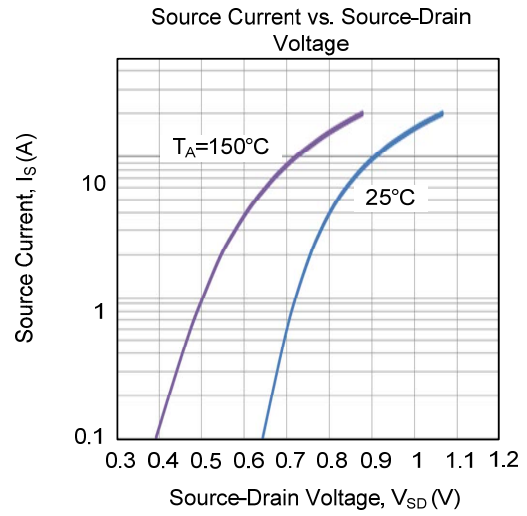
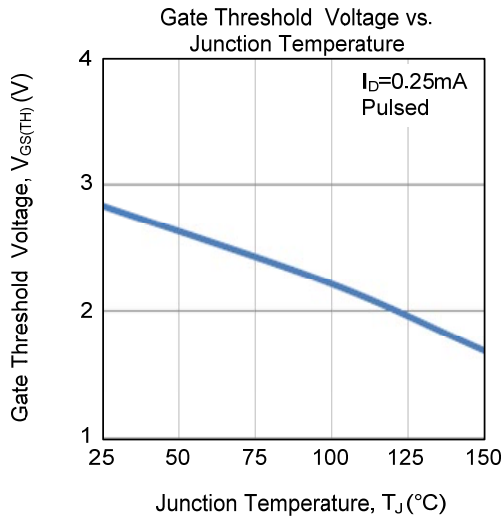
Peak Diode Recovery dv/dt Test Circuit & Waveforms



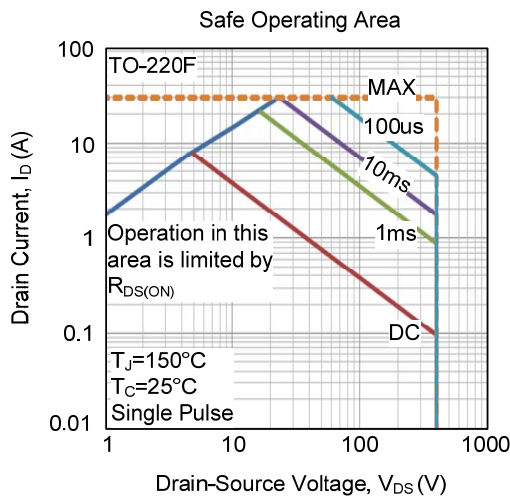
### TYPICAL CHARACTERISTICS



### TYPICAL CHARACTERISTICS (Cont.)



■ TYPICAL CHARACTERISTICS (Cont.)



UTC assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all UTC products described or contained herein. UTC products are not designed for use in life support appliances, devices or systems where malfunction of these products can be reasonably expected to result in personal injury. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner. UTC reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.